WHAT IS CLAIMED IS:

1. A method of reducing noise and power supply instability problems during OBIRCH analysis testing of circuit elements requiring a precise operating or core voltage comprising the steps of:

providing an OBIRCH analysis circuit having I/O terminals;

connecting a circuit element to be tested to said OBIRCH analysis circuitry;

connecting a power source having a positive and a negative output across said I/O terminals for providing a known voltage to said OBIRCH analysis circuit;

connecting a diode circuit across said positive and negative outputs of said power source, said diode circuit comprising the steps of connecting the anode of a common or bi-polar diode to said positive output and connecting the cathode of said bi-polar diode to the anode of the first one of a plurality of Schottky diodes serially connected, cathode-to-anode, and coupling said negative output of said power source to the cathode end of said plurality of serially connected Schottky diodes, such that a precise and different voltage selection is available at the anode of each Schottky diode of said series;

connecting one of said precise voltage selections to said circuit element to be tested as its core or operating voltage; and

running an OBIRCH circuit analysis on said circuit element to be tested.

2. The method of claim 1 wherein said diode circuit further comprises a second common or bi-polar diode having its anode connected at the cathode end of said plurality of serially connected Schottky diodes and with its cathode connected to the negative terminal of said power source.

3. The method of claim 1 wherein said step of connecting a power source comprises connecting a power source having an output voltage of approximately 3.6 volts.

4. The method of claim 3 wherein said step of connecting a plurality of Schottky diodes comprises the step of connecting seven Schottky diodes having a forward voltage drop of approximately 0.3 volts each.

5. Circuitry for reducing noise and power supply instability problems during OBIRCH analysis testing of circuit elements on an integrated circuit requiring a precise operating or core voltage comprising:

an OBIRCH analysis circuit having I/O terminals;

an integrated circuit to be tested connected to said OBIRCH analysis circuitry;

a power source having a positive and a negative output connected across said I/O terminals for providing a precise voltage to said OBIRCH analysis circuit;

a diode circuit connected across said positive and negative outputs of said power source, said diode circuit comprising a common or bi-polar diode having its anode connected to said positive output and its cathode connected to the anode of a plurality of Schottky diodes serially connected, cathode-to-anode, said negative output of said power source being coupled to the cathode of the end Schottky diode of said plurality of serially connected diodes, such that a precise and different voltage selection is available at the anode of each Schottky diode of said series; and

said integrated circuit to be tested connected to one of said precise voltage selections as its core or operating voltage.

6. The circuitry of claim 5 further comprising a second common or bi-polar diode connected at the other end of said plurality of serially connected Schottky diodes and with its cathode connected to the negative terminal of said power source.

7. The circuitry of claim 5 wherein said power source has an output voltage of approximately 3.6 volts.

8. The circuitry of claim 7 wherein said plurality of serially connected Schottky diodes comprises seven serially connected diodes each having a forward voltage drop of approximately 0.3 volts each.